

TSMC-99-646B



July 17, 2001

#3/98/98107  
Rade

To: Commissioner of Patents and Trademarks  
Washington, D.C. 20231

Fr: George O. Saile, Reg. No. 19,572  
20 McIntosh Drive  
Poughkeepsie, N.Y. 12603

Subject:

Serial No. 09/846,536 05/02/01

Wen-Ting Chu, Hsin-Ming Chen

A NOVEL SELF-ALIGNED, LOW CONTACT  
RESISTANCE, VIA FABRICATION PROCESS

Grp. Art Unit: 2811  
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INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation  
In An Application.

The following Patents and/or Publications are submitted to  
comply with the duty of disclosure under CFR 1.97-1.99 and  
37 CFR 1.56. Copies of each document is included herewith.

U.S. Patent 5,834,369 to Murakami et al., "Method of  
Preventing Diffusion Between Interconnect and Plug", discloses  
a method for a Al line over an W-plug.

U.S. Patent 5,994,213 to Wang et al., "Aluminum Plug  
Process", teaches an Al plug process.

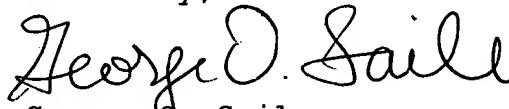
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TC 2800 MAIL ROOM

U.S. Patent 5,956,609 to Lee et al., "Method for Reducing Stress and Improving Step-Coverage of Tungsten Interconnects and Plugs", discusses a plug/line process.

U.S. Patent 5,472,912 to Miller, "Method of Making an Integrated Circuit Structure by Using a Non-Conductive Plug", discloses a non-conductive plug that partially fills the via hole.

U.S. Patent 5,913,143 to Harakawa, "Method of Making a MultiLayer Interconnection of Semiconductor Device Using Plug", discusses an inter-level insulating film formed on a first Al film and a contact hole formed to partly expose the first Al film.

Sincerely,

A handwritten signature in cursive script that reads "George O. Saile". The signature is written in dark ink and is positioned above the printed name and registration number.

George O. Saile,  
Reg. No. 19572



Form PTO-1449

INFORMATION DISCLOSURE CITATION  
IN AN APPLICATION

(Use several sheets if necessary)

Doc No. (Optional)

TSMC-9906468

Application Number

09/846,536

Applicant

Wen-Ting Chu et al.

Filing Date

05/02/01

Group Art Unit

2811

## U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	ALSO DATE IF APPROPRIATE
ON	5834369	11/10/98	Murakami et al.	438	625	1/31/96
ON	5994213	11/30/99	Wang et al.	438	622	2/9/98
ON	5956609	9/21/99	Lee et al.	438	627	8/11/97
ON	5913143	6/15/99	Harakawa	438	627	4/1/97
ON	5472912	12/5/95	Miller	437	194	11/7/94
TC 2800 MAIL ROOM						
JUL 20 2001						
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## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Portion Pages, Etc.)


EXAMINER

ON

DATE CONSIDERED

11/15/01

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through